Test Technology Newsletter

April 2023

**The Newsletter of the Test Technology Technical Community
of the IEEE Computer Society**

Editor: Stefano Di Carlo

TTTC News

The TTTC website always lists the latest features and information for its visitors! To find out more, please visit the website at http://www.ieee-tttc.org/

PAST EVENTS REPORTS

24th IEEE Latin-American Test Symposium
21-24th March 2023
Veracruz, Mexico
https://www-elec.inaoep.mx/~LATS2023/

The IEEE Latin-American Test Symposium (LATS) is a recognized forum dedicated to presenting and discussing scientific results, emerging ideas, applications, hot topics, and new trends in the area of electronic-based circuits and system testing, reliability, and security. LATS is attended by professionals from all over the world, in particular from Latin-America.
In its 24th edition LATS was organized in Varacruz Mexico. The technical program featured four interesting days including two tutorials, four keynote talks and several special and regular paper sessions.

The 19th IEEE Workshop on Silicon Errors in Logic – System Effects (SELSE) 2023
March 23–24, 2023
Virtual Event
https://selse.org/

The growing complexity and shrinking geometries of modern manufacturing technologies are making high-density, low-voltage devices increasingly susceptible to the influences of electrical noise, process variation, transistor aging, and the effects of natural radiation. The system-level impact of these errors can be far-reaching, both in safety-critical aerospace and automotive applications and for high-performance applications. In the context of space and automotive applications, the rapid market evolution and the increase in complexity of electronic devices call for new methodologies to verify and increase the reliability of current and future COTS products.
SELSE provides a unique forum for discussion of current research and practice in system-level error management. SELSE presents papers that address the system-level effects of errors from a variety of perspectives: architectural, logical, circuit-level, and semiconductor processes. Case studies in real-world contexts are also welcome.
Following the success of the previous edition SELSE was organized as virtual event favoring the participation of a large audience from all over the world with a rich two days technical program.

Design, Automation, and Test in Europe (DATE) Conference 2023
17-19 April 2023
Antwerp, BE
https://www.date-conference.com/

The DATE conference is the main European event bringing together designers and design automation users, researchers, and vendors as well as specialists in the hardware and software design, test and manufacturing of electronic circuits and systems. DATE puts a strong emphasis on both technology and systems, covering ICs/SoCs, reconfigurable hardware and embedded systems as well as embedded software. The three-day event consisted of a conference with regular papers, late breaking results papers and extended abstracts, complemented by timely keynotes, special days, focus sessions, embedded tutorials, half-day workshops and multi-partner project sessions. The event also hosted the Young People Programme and newly introduced unplugged sessions fostering the networking and the exchange of information on relevant issues, recent research outcomes and career opportunities.
For its 2023 edition, DATE presented itself in a renewed format: after three years of online editions due to COVID-19, DATE 2023 focused on interaction as well as reinforcing

and rebuilding links in the community. Rather than spreading the attendance throughout an entire week, DATE was condensed to three days, most regular papers were presented in a renewed format of technical sessions focusing on live interactions making sure that the community could do what conferences are for: meeting, discussing and exchanging.

The 40th IEEE VLSI Test Symposium (VTS) 2023
24-26 April 2023
San Diego, USA
https://tttc-vts.org/

The IEEE VLSI Test Symposium (VTS) explores emerging trends and novel concepts in testing, debugging and repair of microelectronic circuits and systems.
After several virtual edition VTS 2023 moved back to an in-person event. The symposium took place on April 24-26, 2023, at the Hyatt Regency Mission Bay Spa & Marina, 1441 Quivira Road, San Diego, CA, USA.
VTS put particular emphasis on enlarging its scope. Apart from the traditional test topics this year the VTS program focused on silent data corruption - reliability and security aspects of AI - machine learning systems - neuromorphic devices - and quantum computing. The event was a real success with a high attendance and interesting discussions.

CLOSE EVENTS

The International Symposium on Design and Diagnostics of Electronic Circuits and Systems (DDECS) 2023
May 3-5, 2023
Tallinn, Estonia
http://www.ddecs.org/

The International Symposium on Design and Diagnostics of Electronic Circuits and Systems (DDECS) provides a forum for exchanging ideas, discussing research results, and presenting practical applications in the areas of design, test, security and diagnosis of electronic digital and analog circuits and systems. The 26th edition of the DDECS Symposium will be held in Tallinn, Estonia's capital and one of the best-preserved medieval cities in Europe. The symposium is organized by Tallinn University of Technology (TalTech) and technically co-sponsored by IEEE Council on Electronic Design Automation (CEDA).

28th IEEE European Test Symposium 2023 (ETS)
May 22-26
Venice, Italy | Hybrid conference
https://cas.polito.it/ETS23/

The IEEE European Test Symposium (ETS) is Europe's premier forum dedicated to presenting and discussing scientific results, emerging ideas, hot topics, and new trends, industrial case-studies and applications, in the area of electronic-based circuits and system testing, reliability, safety, security and validation. The 2023 edition of ETS will be a hybride one. ETS'23 is organized jointly by CNRS-INL and Politecnico di Torino, which co-sponsor the event together with the IEEE Council on Electronic Design Automation (CEDA). ETS'23 is technically sponsored by the IEEE Computer Society – Test Technology Technical Council (TTTC).
The program includes keynotes, scientific paper presentations, panels, tutorials, fringe workshops and highlights/demos from industry. Linked to the main ETS'23 symposium, the Test Spring School will be organized.

UPCOMING EVENTS

The 29th IEEE International Symposium on On-Line Testing and Robust System Design (IOLTS) 2023
July 3rd - 5th, 2023
Chania (Crete), Greece
https://iolts.tttc-events.org/

IEEE International Test Conference India (ITC INDIA) 2023
July 23-25, 2023
Bengaluru, India
https://itctestweekindia.org

UPCOMING PAPER SUBMISSION DEADLINES

The 32nd IEEE Asian Test Symposium (ATS) 2023
Oct.14-17, 2023
Beijing, China
https://ats2023.casconf.cn
Submission deadline: June, 11th 2023

NEWSLETTER EDITOR'S INVITATION

I would appreciate input and suggestions about the newsletter from the test community. Please forward your ideas, contributions, and information on awards, conferences, and workshops to Stefano Di Carlo, Control and Computer Engineering Department, Politecnico di Torino, I-10129, Torino, Italy; stefano.dicarlo@polito.it.

Stefano Di Carlo
Editor, TTTC Newsletter

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CONTRIBUTIONS TO THIS NEWSLETTER: Send contributions to

Stefano Di Carlo
Control and Computer Engineering
Politecnico di Torino

I-10129, Torino, Italy
stefano.dicarlo@polito.it
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